



RCE

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Keiji Yada, et al.) Examiner: Kao, Chih Cheng G.
)
Serial No.: 10/719,887) Art Unit: 2882
)
Filed: November 21, 2003) Our Ref: B-5308 621524-7
)
For: "X-RAY MICROSCOPIC INSPECTION APPARATUS") Date: November 9, 2005
)
) Re: <i>Amendment and Response</i>
)

AMENDMENT AND RESPONSE

Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In reply to the final Office Action mailed on August 10, 2005, a response to which is due no later than

November 10, 2005,

the Applicant submits this amendment pursuant to 37 C.F.R. 1.114 together with a Request for Continued Examination. Please find enclosed a check in the amount of \$790.00 for the RCE fee set forth in 37. C.F.R. 1.17(e). Please amend the above-identified application as described below and consider the following remarks. **All amendments and remarks herein are made without prejudice.**

Amendments to the Claims are reflected in the listing of claims that begins on page 2 of this paper.

Amendments to the Drawings begin on page 6 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 7 of this paper.